Applicant(s)/Patent Under Application/Control No. Reexamination 10/798,957 FORSTER ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2821 Hoang V. Nguyen **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 343/895 US-2004/0075616 A1 04-2004 Endo et al. US-6,830,193 B2 12-2004 Tanaka, Masahiko 235/492 В US-С US-D Ε US-US-F US-G US-Н US-1 US-J K US-US-US-FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U V

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